

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/642,592	<b>Applicant(s)/Patent under Reexamination</b> FUKAMI, KATSUYA
<b>Examiner</b> Lien T. Tran	<b>Art Unit</b> 1761	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner